## International Rectifier

## IRFB4610PbF IRFS4610PbF IRFSL4610PbF

HEXFET® Power MOSFET

#### **Applications**

- High Efficiency Synchronous Rectification in SMPS
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits

# G

V <sub>DSS</sub>		100V
R <sub>DS(on)</sub>	typ.	11m $\Omega$
	max.	14m $\Omega$
I <sub>D</sub>		73A

#### **Benefits**

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dI/dt Capability
- Lead-Free

S G D	rear GDS	refr GDS
TO-220AB	D <sup>2</sup> Pak	TO-262
IRFB4610PbF	IRFS4610PbF	IRFSL4610PbF

**Absolute Maximum Ratings** 

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	73	Α
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	52	
I <sub>DM</sub>	Pulsed Drain Current ④	290	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	190	W
	Linear Derating Factor	1.3	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
dV/dt	Peak Diode Recovery ③	7.6	V/ns
T <sub>J</sub>	Operating Junction and	-55 to + 175	°C
T <sub>STG</sub>	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300	
	(1.6mm from case)		
	Mounting torque, 6-32 or M3 screw	10lb·in (1.1N·m)	

#### **Avalanche Characteristics**

E <sub>AS (Thermally limited)</sub>	Single Pulse Avalanche Energy ©	370	mJ
I <sub>AR</sub>	Avalanche Current ①	See Fig. 14, 15, 16a, 16b,	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ④		mJ

#### **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ®		0.77	
$R_{\theta CS}$	Case-to-Sink, Flat Greased Surface , TO-220	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient, TO-220 ®	<del></del>	62	
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) , D²Pak ⑦®		40	

#### Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.085		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA①
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		11	14	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 44A ⊕
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$ , $I_D = 100\mu A$
I <sub>DSS</sub>	Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 100V, V_{GS} = 0V$
				250		$V_{DS} = 100V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			200	nA	V <sub>GS</sub> = 20V
	Gate-to-Source Reverse Leakage			-200		V <sub>GS</sub> = -20V
$R_G$	Gate Input Resistance		1.5		Ω	f = 1MHz, open drain

#### Dynamic @ T<sub>J</sub> = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	73			S	$V_{DS} = 50V, I_{D} = 44A$
$Q_g$	Total Gate Charge		90	140	nC	I <sub>D</sub> = 44A
$Q_{gs}$	Gate-to-Source Charge		20			$V_{DS} = 80V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		36			V <sub>GS</sub> = 10V ④
t <sub>d(on)</sub>	Turn-On Delay Time		18		ns	$V_{DD} = 65V$
t <sub>r</sub>	Rise Time		87			I <sub>D</sub> = 44A
t <sub>d(off)</sub>	Turn-Off Delay Time		53			$R_G = 5.6\Omega$
t <sub>f</sub>	Fall Time		70			V <sub>GS</sub> = 10V ④
C <sub>iss</sub>	Input Capacitance		3550		pF	$V_{GS} = 0V$
C <sub>oss</sub>	Output Capacitance		260			$V_{DS} = 50V$
C <sub>rss</sub>	Reverse Transfer Capacitance		150			f = 1.0MHz
C <sub>oss</sub> eff. (ER)	Effective Output Capacitance (Energy Related)		330		1	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 0V to 80V ⑥, See Fig.11
C <sub>oss</sub> eff. (TR)	Effective Output Capacitance (Time Related)		380		1	$V_{GS} = 0V$ , $V_{DS} = 0V$ to 80V $\odot$ , See Fig. 5

#### **Diode Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			73	Α	MOSFET symbol
	(Body Diode)					showing the
I <sub>SM</sub>	Pulsed Source Current			290		integral reverse
	(Body Diode) ①					p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 44A, V_{GS} = 0V \oplus$
t <sub>rr</sub>	Reverse Recovery Time		35	53	ns	$T_J = 25^{\circ}C$ $V_R = 85V$ ,
			42	63		$T_J = 125^{\circ}C$ $I_F = 44A$
Q <sub>rr</sub>	Reverse Recovery Charge		44	66	nC	$T_J = 25^{\circ}C$ di/dt = 100A/ $\mu$ s @
			65	98		$T_J = 125^{\circ}C$
I <sub>RRM</sub>	Reverse Recovery Current		2.1		Α	$T_J = 25^{\circ}C$
t <sub>on</sub>	Forward Turn-On Time	Intrins	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)			

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by  $T_{Jmax}$ , starting  $T_J$  = 25°C, L = 0.39mH  $R_G$  = 25 $\Omega$ ,  $I_{AS}$  = 44A,  $V_{GS}$  =10V. Part not recommended for use above this value.
- $\label{eq:loss_def} \mbox{ } \mbox{ } \mbox{I}_{SD} \leq 44A, \mbox{ } \mbox{di/dt} \leq 660A/\mu s, \mbox{ } \mbox{V}_{DD} \leq \mbox{V}_{(BR)DSS}, \mbox{ } \mbox{T}_{J} \leq 175^{\circ}\mbox{C}.$
- 4 Pulse width  $\leq$  400 $\mu$ s; duty cycle  $\leq$  2%.

- ©  $C_{oss}$  eff. (ER) is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- $\ensuremath{\$}\ R_{\theta}$  is measured at  $T_J$  approximately  $90^{\circ}C$

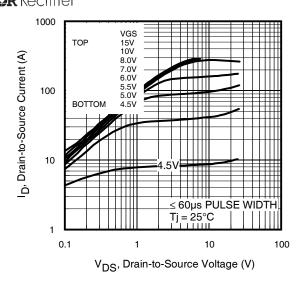


Fig 1. Typical Output Characteristics

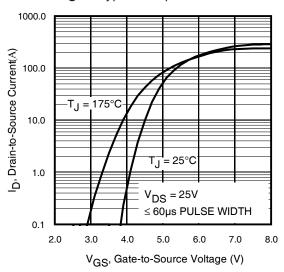
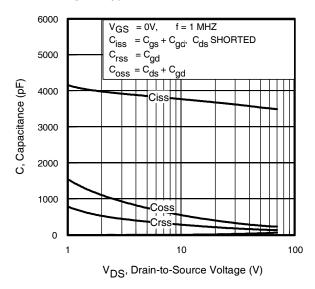


Fig 3. Typical Transfer Characteristics



**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage www.irf.com

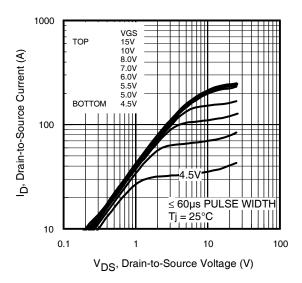


Fig 2. Typical Output Characteristics

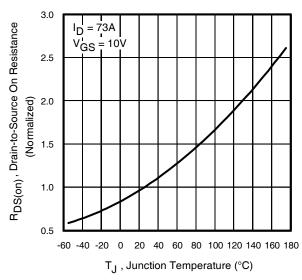


Fig 4. Normalized On-Resistance vs. Temperature

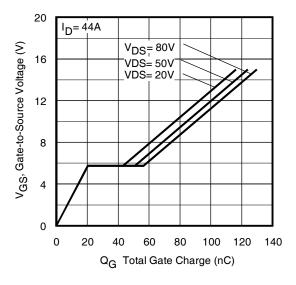


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

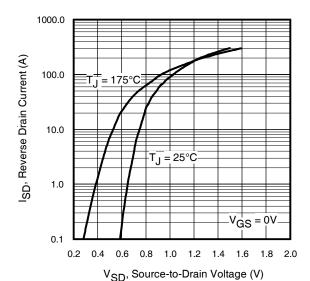
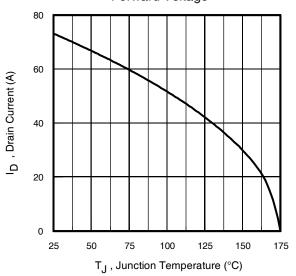


Fig 7. Typical Source-Drain Diode Forward Voltage



**Fig 9.** Maximum Drain Current vs. Case Temperature

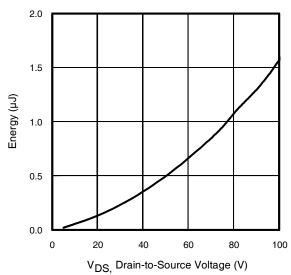


Fig 11. Typical C<sub>OSS</sub> Stored Energy

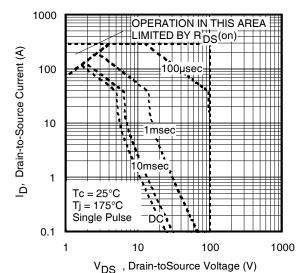


Fig 8. Maximum Safe Operating Area

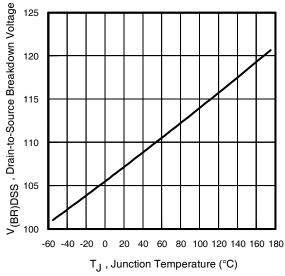


Fig 10. Drain-to-Source Breakdown Voltage

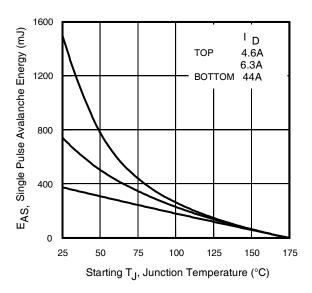


Fig 12. Maximum Avalanche Energy Vs. DrainCurrent www.irf.com

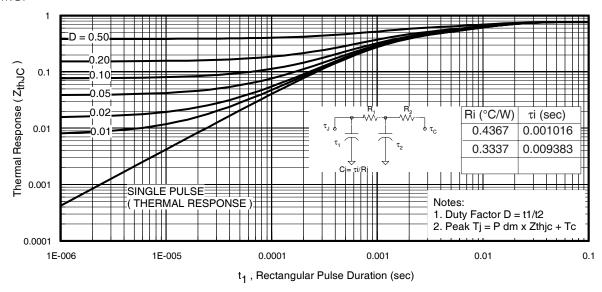


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

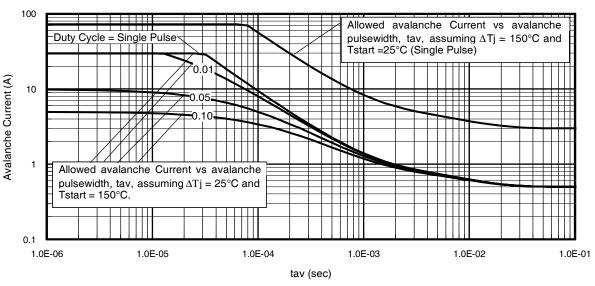


Fig 14. Typical Avalanche Current vs. Pulsewidth

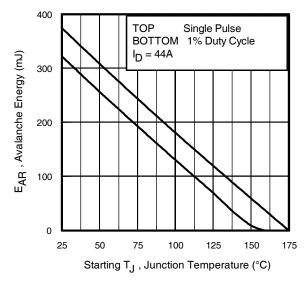


Fig 15. Maximum Avalanche Energy vs. Temperature

## Notes on Repetitive Avalanche Curves , Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption:
- Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.
- Safe operation in Avalanche is allowed as long as neither T<sub>jmax</sub> nor I<sub>av (max)</sub> is exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 16a, 16b.
- 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 14, 15).
  - $t_{av}$  = Average time in avalanche.
  - D = Duty cycle in avalanche =  $t_{av} \cdot f$
  - $Z_{th,JC}(D, t_{av})$  = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D~(ave)} &= 1/2~(~1.3 \cdot BV \cdot I_{av}) = \triangle T/~Z_{thJC} \\ I_{av} &= 2\triangle T/~[1.3 \cdot BV \cdot Z_{th}] \\ E_{AS~(AR)} &= P_{D~(ave)} \cdot t_{av} \end{split}$$

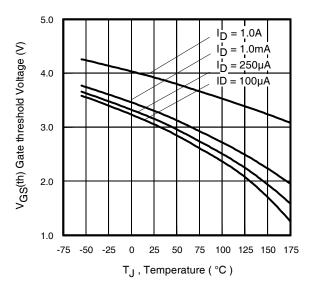


Fig 16. Threshold Voltage Vs. Temperature

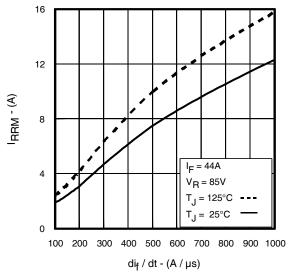


Fig. 18 - Typical Recovery Current vs. dif/dt

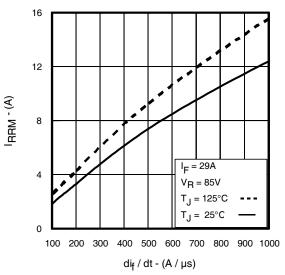


Fig. 17 - Typical Recovery Current vs. di<sub>f</sub>/dt

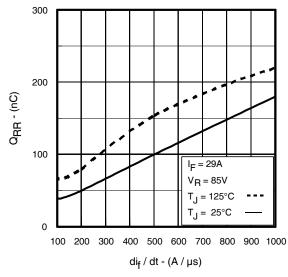


Fig. 19 - Typical Stored Charge vs. dif/dt

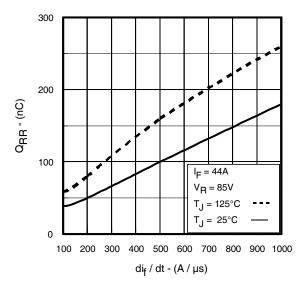


Fig. 20 - Typical Stored Charge vs. dif/dt

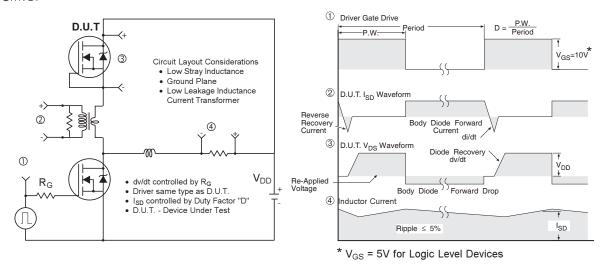


Fig 21. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

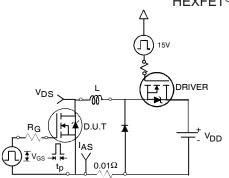


Fig 22a. Unclamped Inductive Test Circuit

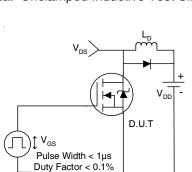


Fig 23a. Switching Time Test Circuit

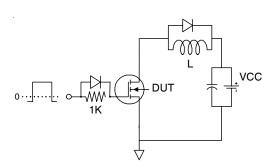


Fig 24a. Gate Charge Test Circuit www.irf.com

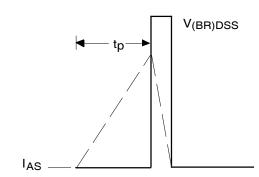


Fig 22b. Unclamped Inductive Waveforms

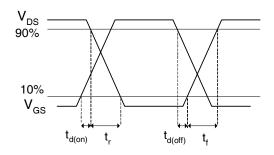


Fig 23b. Switching Time Waveforms

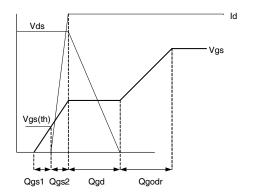
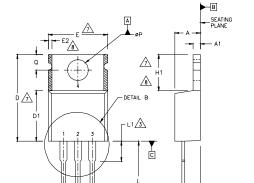


Fig 24b. Gate Charge Waveform

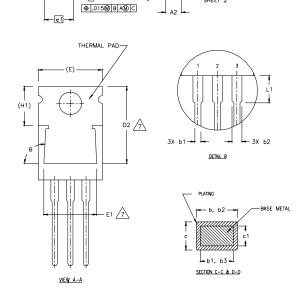
#### IRF/B/S/SL4610PbF

## TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



2X e



### International IOR Rectifier

#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
- DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS]. LEAD DIMENSION AND FINISH UNCONTROLLED IN L1
- DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE, THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- DIMENSION b1 & c1 APPLY TO BASE METAL ONLY. CONTROLLING DIMENSION : INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.

SYMBOL	MILLIM	ETERS	INCHES		
	MIN.	MAX.	MIN.	MAX.	NOTES
Α	3,56	4,82	.140	.190	
A1	0.51	1.40	.020	.055	
A2	2.04	2,92	.080	.115	
b	0.38	1.01	.015	.040	
b1	0,38	0.96	,015	.038	5
b2	1,15	1,77	.045	.070	
ь3	1,15	1.73	.045	.068	
С	0.36	0.61	.014	.024	
c1	0,36	0.56	.014	.022	5
D	14.22	16.51	.560	.650	4
D1	8,38	9.02	.330	.355	
D2	12.19	12.88	.480	.507	7
E	9.66	10.66	.380	.420	4,7
E1	8.38	8.89	.330	.350	7
e	2.54	BSC	.100 .200	BSC	]
e1	5.0	J8	.200	BSC	
H1	5.85	6.55	.230	.270	7,8
L	12.70	14.73	.500	.580	
L1	-	6.35	-	.250	3
øΡ	3.54	4.08	.139	.161	
Q	2.54	3.42	.100	.135	
ø	90"-	-93"	90*-	90*-93*	

#### LEAD ASSIGNMENTS

HEXFET

1,- GATE 2.- DRAIN 3.- SOURCE

#### IGBTs, CoPACK

1,- GATE 2,- COLLECTOR 3,- EMITTER

#### DIODES

1.- ANODE/OPEN 2.- CATHODE 3.- ANODE

## TO-220AB Part Marking Information

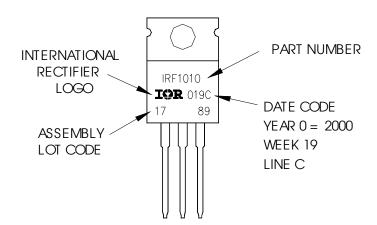
EXAMPLE: THIS IS AN IRF1010

LOT CODE 1789

ASSEMBLED ON WW 19, 2000

IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead - Free"



TO-220AB packages are not recommended for Surface Mount Application.

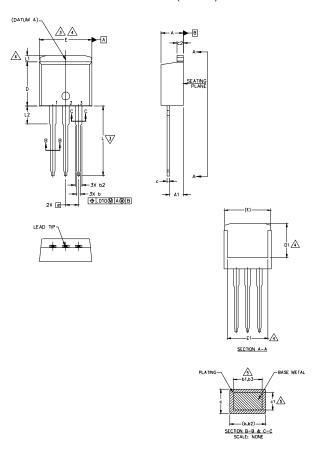
- 1. For an Automotive Qualified version of this part please seehttp://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

8 www.irf.com

#### IRF/B/S/SL4610PbF

## TO-262 Package Outline

Dimensions are shown in millimeters (inches)



#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

/3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. CONTROLLING DIMENSION: INCH.
- 7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

S Y M B O L			N		
B	MILLIM	ETERS	INC	HES	O T E S
L	MIN.	MAX.	MIN.	MAX.	S
Α	4.06	4.83	.160	.190	
A1	2.03	3.02	.080	.119	
ь	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	5
b2	1,14	1,78	.045	.070	
ь3	1.14	1,73	.045	.068	5
С	0.38	0.74	.015	.029	
c1	0.38	0.58	.015	.023	5
c2	1,14	1,65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	-	.270	-	4
E	9.65	10.67	.380	.420	3,4
E1	6.22	-	.245		4
е	2.54	BSC	.100 BSC		
L	13.46	14,10	.530	.555	
L1	-	1,65	-	.065	4
L2	3.56	3.71	.140	.146	

#### LEAD ASSIGNMENTS

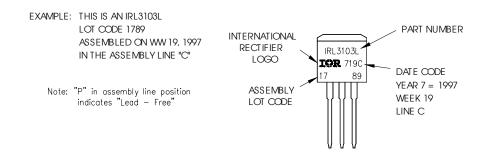
#### **HEXFET**

- 1.- GATE
- 2.- DRAIN 3.- SOURCE
- 4.- DRAIN

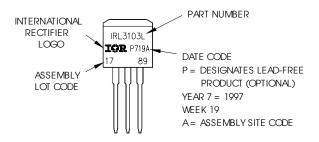
#### IGBTs, CoPACK

- 1.- GATE 2.- COLLECTOR
- 3.- EMITTER 4.- COLLECTOR

TO-262 Part Marking Information







#### Notes:

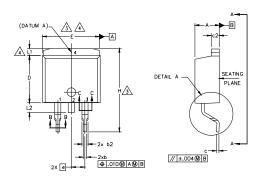
- 1. For an Automotive Qualified version of this part please seehttp://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

#### IRF/B/S/SL4610PbF

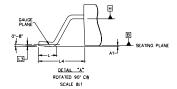
## International **TOR** Rectifier

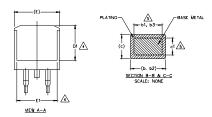
## D<sup>2</sup>Pak (TO-263AB) Package Outline

Dimensions are shown in millimeters (inches)









#### NOTES:

- 1, DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

O.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S			Ŋ		
M B O L	MILLIM	ETERS	INC	HES	O T E S
L	MIN.	MAX.	MIN.	MAX.	S
Α	4.06	4.83	.160	.190	
A1	0.00	0.254	.000	.010	
ь	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	5
b2	1,14	1.78	.045	.070	
ь3	1,14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
c1	0.38	0.58	.015	.023	5
c2	1,14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	-	.270		4
E	9.65	10,67	.380	.420	3,4
E1	6.22	-	.245		4
е	2.54	BSC	.100	BSC	
н	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	-	1.65	-	.066	4
L2	1.27	1.78	-	.070	
L3	0.25	BSC	.010	BSC	
L4	4.78	5.28	.188	.208	

#### LEAD ASSIGNMENTS

#### <u>HEXFET</u>

1.- GATE 2, 4.- DRAIN 3.- SOURCE

#### IGBTs, CoPACK

1.- GATE
2, 4.- COLLECTOR
3.- EMITTER

#### DIODES

- 1.- ANODE \*
  2. 4.- CATHODE
  3.- ANODE
- \* PART DEPENDENT.

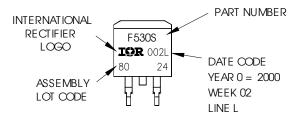
## D<sup>2</sup>Pak (TO-263AB) Part Marking Information

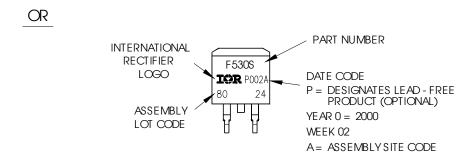
EXAMPLE: THIS IS AN IRF530S WITH

LOT CODE 8024

ASSEMBLED ON WW 02, 2000 IN THE ASSEMBLY LINE "L"

Note: "P" in assembly line position indicates "Lead — Free"

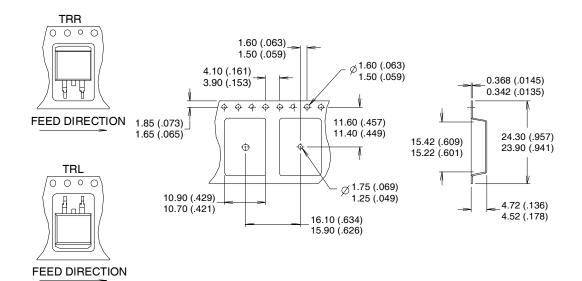


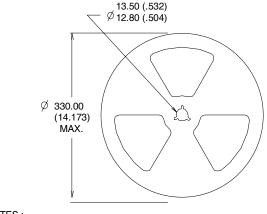


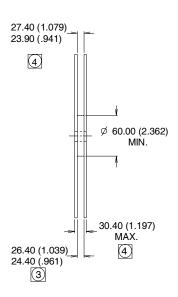
#### Notes:

- 1. For an Automotive Qualified version of this part please see http://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

## D<sup>2</sup>Pak (TO-263AB) Tape & Reel Information







#### NOTES:

- 1. COMFORMS TO EIA-418.
- 2. CONTROLLING DIMENSION: MILLIMETER.
- 3 DIMENSION MEASURED @ HUB.
- 4 INCLUDES FLANGE DISTORTION @ OUTER EDGE.

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market.

Qualification Standards can be found on IR's Web site.



IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105

TAC Fax: (310) 252-7903

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